

TC74HC4094P/F

TC74HC4094P/F 8-BIT SHIFT AND STORE REGISTER (3-STATE)

The TC74HC4094 is a high speed CMOS 8-STAGE SHIFT-AND-STORE REGISTER fabricated with silicon gate C²MOS technology. It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. This device consists of an 8-bit shift register and a 8-bit latch with 3-state output buffer. Data is shifted serially through the shift register on the positive going transition of the clock input signal. The output of the last stage (Qs) can be used to cascade several devices. Data on the Qs output is transferred to a second output (Qs') on the following negative transition of the clock input signal. The data of each stage of the shift register is provided to a latch, which latches data on the negative going transition of the STROBE input signal. When STROBE input is held high, data propagates through the latch to a 3-state output buffer. This buffer is enabled when OUTPUT ENABLE input is taken high. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

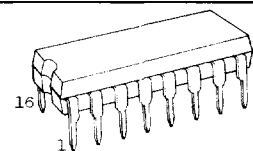
FEATURES

- High Speed $f_{MAX}=42\text{MHz(Typ.)}$ at $V_{CC}=5\text{V}$
- Low Power Dissipation $I_{CC}=4\mu\text{A(Max.)}$ at $T_a=25^\circ\text{C}$
- High Noise Immunity $V_{NIH}=V_{NIL}=28\% V_{CC(\text{Min.})}$
- Output Drive Capability 10 LSTTL Loads
- Symmetrical Output Impedance $|I_{OH}|=I_{OL}=4\text{mA}$
- Balanced Propagation Delays $t_{PLH}\approx t_{PHL}$
- Wide Operating Voltage Range $V_{CC(\text{opr.})}=2\text{V}\sim 6\text{V}$
- Pin and Function Compatible with 4094B

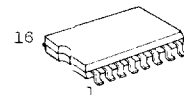
ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V_{CC}	$-0.5 \sim 7$	V
DC Input Voltage	V_{IN}	$-0.5 \sim V_{CC}+0.5$	V
DC Output Voltage	V_{OUT}	$-0.5 \sim V_{CC}+0.5$	V
Input Diode Current	I_{IK}	± 20	mA
Output Diode Current	I_{OK}	± 20	mA
DC Output Current	I_{OUT}	± 25	mA
DC V_{CC} /Ground Current	I_{CC}	± 50	mA
Power Dissipation	P_D	500(DIP)* 180(MFP)	mW
Storage Temperature	T_{stg}	$-65 \sim 150$	$^\circ\text{C}$
Lead Temperature 10sec	T_L	300	$^\circ\text{C}$

* 500mW in the range of $T_a=-40^\circ\sim 65^\circ\text{C}$ and from $T_a=65^\circ\text{C}$ up to 85°C derating factor of $-10\text{mW}/^\circ\text{C}$ shall be applied until 300mW.

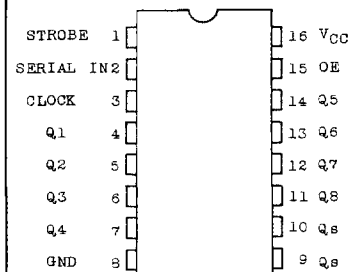


DIP16 (3D16A-P)



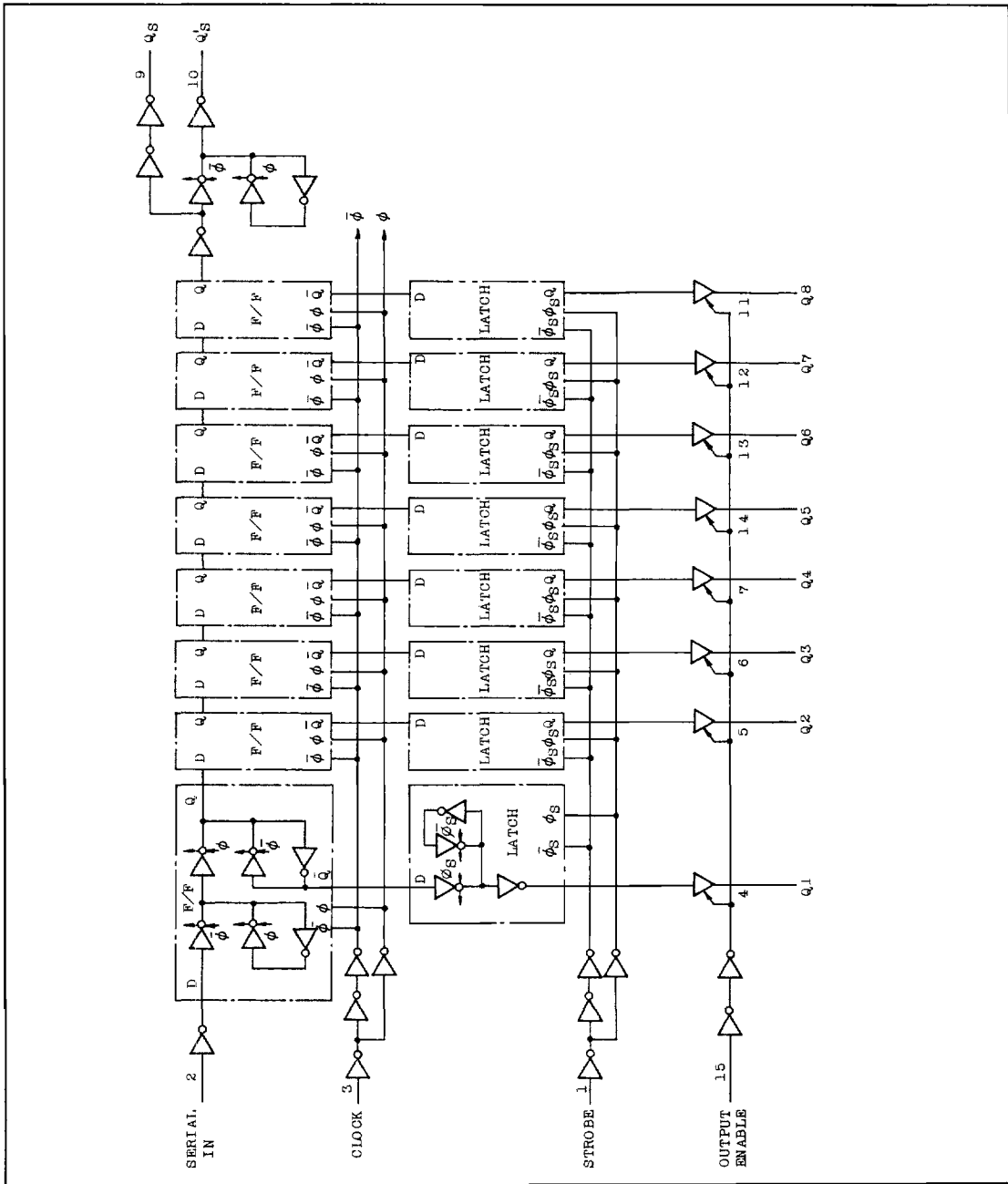
MFP16 (F16GC-P)

PIN ASSIGNMENT

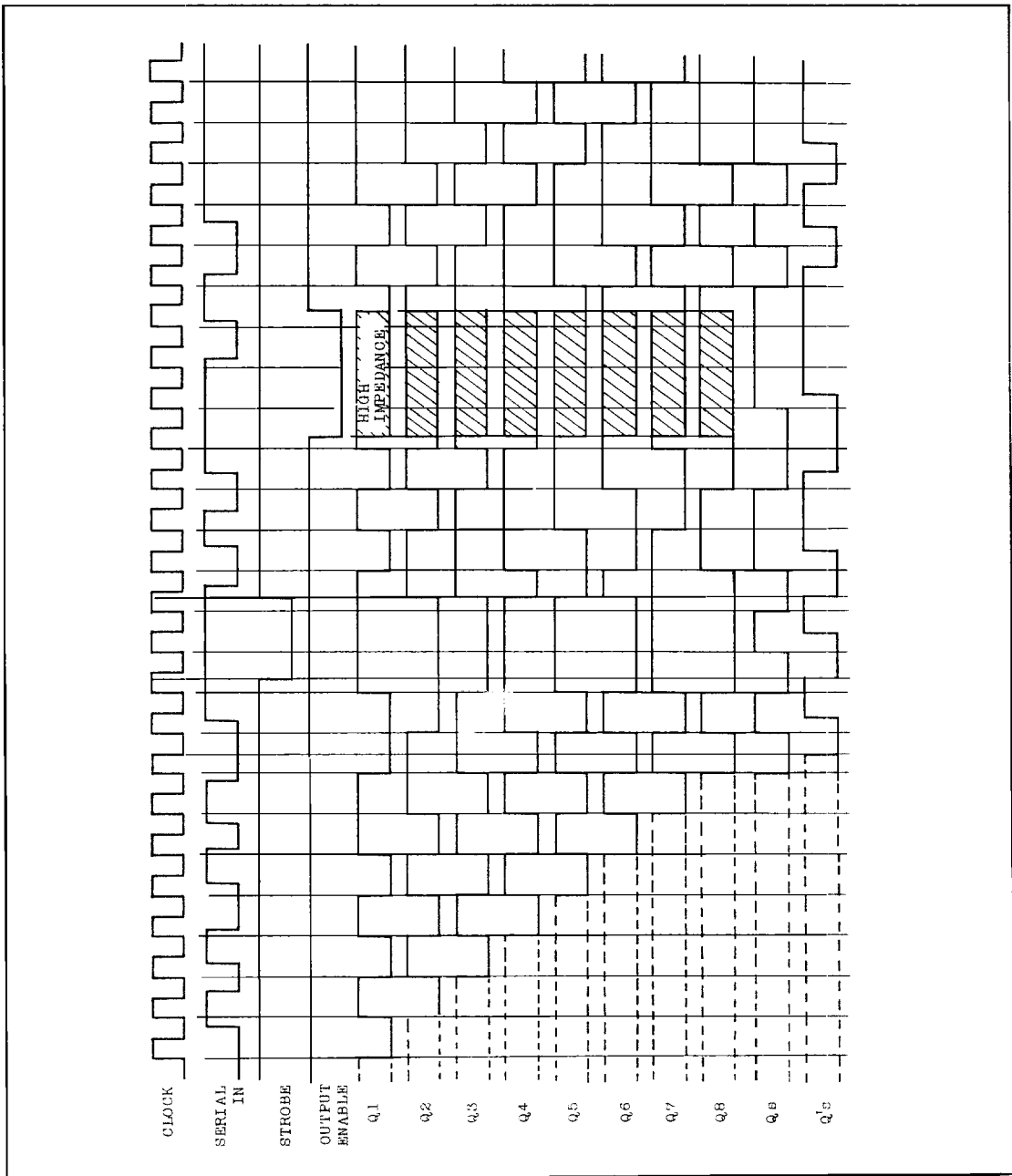


(TOP VIEW)

LOGIC DIAGRAM



TIMING CHART



TRUTH TABLE

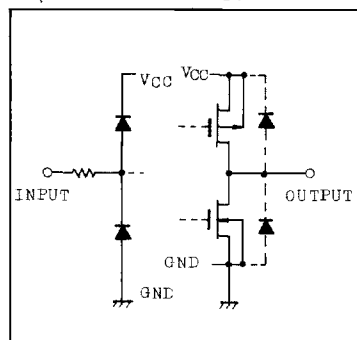
CK	OE	ST	SI	PARA.OUT		SERI.OUT	
				Q ₁	Q _n	Q _s	Q' _s
	H	H	L	L	Q _{n-1}	Q ₇	NC
	H	H	H	H	Q _{n-1}	Q ₇	NC
	H	L	X	NC	NC	Q ₇	NC
	L	X	X	Z	Z	Q ₇	NC
	H	X	X	NC	NC	NC	Q _s
	L	X	X	Z	Z	NC	Q _s

X : DON'T CARE
 NC: NO CHANGE
 Z : HIGH IMPEDANCE

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	LIMIT	UNIT
Supply Voltage	V _{CC}	2 ~ 6	V
Input Voltage	V _{IN}	0 ~ V _{CC}	V
Output Voltage	V _{OUT}	0 ~ V _{CC}	V
Operating Temperature	T _{opr}	-40 ~ 85	°C
Input Rise and Fall Time	t _r , t _f	0 ~ 1000 (V _{CC} =2.0V) 0 ~ 500 (V _{CC} =4.5V) 0 ~ 400 (V _{CC} =6.0V)	ns

INPUT and OUTPUT EQUIVALENT CIRCUIT



DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	Ta=25°C			Ta=-40~85°C		UNIT		
			V _{CC}	MIN.	TYP.	MAX.	MIN.		MAX.	
High-Level Input Voltage	V _{IH}		2.0	1.5	-	-	1.5	-	V	
			4.5	3.15	-	-	3.15	-		
			6.0	4.2	-	-	4.2	-		
Low-Level Input Voltage	V _{IL}		2.0	-	-	0.5	-	0.5	V	
			4.5	-	-	1.35	-	1.35		
			6.0	-	-	1.8	-	1.8		
High-Level Output Voltage	V _{OH}	V _{IN} =V _{IH} or V _{IL}	I _{OH} =-20μA	2.0	1.9	2.0	-	1.9	-	V
				4.5	4.4	4.5	-	4.4	-	
				6.0	5.9	6.0	-	5.9	-	
			I _{OH} =-4mA	4.5	4.18	4.31	-	4.13	-	
				6.0	5.68	5.80	-	5.63	-	
				I _{OH} =-5.2mA	6.0	5.68	5.80	-	5.63	

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DC ELECTRICAL CHARACTERISTICS (Continued)

PARAMETER	SYMBOL	TEST CONDITION	V _{CC}	Ta=25°C			Ta=-40~85°C		UNIT	
				MIN.	TYP.	MAX.	MIN.	MAX.		
Low-Level Output Voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} =20μA	2.0	-	0.0	0.1	-	0.1	V
				4.5	-	0.0	0.1	-	0.1	
		I _{OL} =4mA	6.0	-	0.0	0.1	-	0.1		
		I _{OL} =5.2mA	4.5	-	0.17	0.26	-	0.33		
			6.0	-	0.18	0.26	-	0.33		
3-State Output Off-State Current	I _{OZ}	V _{IN} =V _{IH} or V _{IL} V _{OUT} =V _{CC} or GND	6.0	-	-	±0.5	-	±5.0	μA	
Input Leakage Current	I _{IN}	V _{IN} =V _{CC} or GND	6.0	-	-	±0.1	-	±1.0	μA	
Quiescent Supply Current	I _{CC}	V _{IN} =V _{CC} or GND	6.0	-	-	4.0	-	40.0		

AC ELECTRICAL CHARACTERISTICS (C_L=50pF, INPUT t_r=t_f=6ns)

PARAMETER	SYMBOL	TEST CONDITION	V _{CC}	25°C			-40 ~ 85°C		UNIT
				MIN.	TYP.	MAX.	MIN.	MAX.	
Output Transition Time	t _{TLH} t _{THL}		2.0	-	30	75	-	95	ns
			4.5	-	8	15	-	19	
			6.0	-	7	13	-	16	
Propagation Delay Time (CLOCK - Qn)	t _{PLH} t _{PHL}		2.0	-	140	270	-	340	ns
			4.5	-	35	54	-	68	
			6.0	-	30	46	-	58	
Propagation Delay Time (CLOCK - Qs, Qs')	t _{PLH} t _{PHL}		2.0	-	104	200	-	250	ns
			4.5	-	26	40	-	50	
			6.0	-	22	34	-	43	
Propagation Delay Time (STROBE - Qn)	t _{PLH} t _{PHL}		2.0	-	135	210	-	265	ns
			4.5	-	27	42	-	53	
			6.0	-	23	36	-	45	
Maximum Clock Frequency	f _{MAX}		2.0	4	10	-	3	-	MHz
			4.5	20	38	-	16	-	
			6.0	24	45	-	19	-	
Minimum Clock Pulse Width	t _w (H) t _w (L)		2.0	-	35	100	-	125	ns
			4.5	-	9	20	-	25	
			6.0	-	8	17	-	21	
Minimum Strobe Pulse Width	t _w (H)		2.0	-	35	100	-	125	ns
			4.5	-	9	20	-	25	
			6.0	-	8	17	-	21	

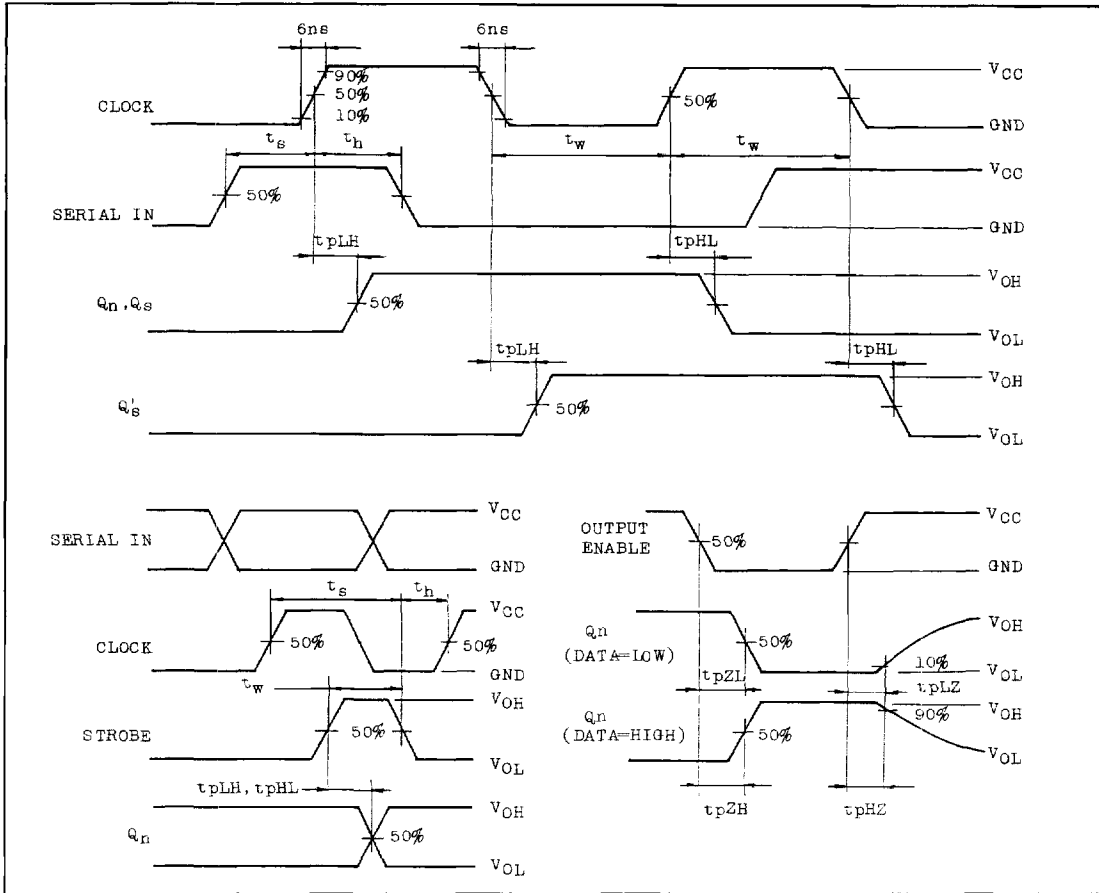
AC ELECTRICAL CHARACTERISTICS (Continued)

PARAMETER	SYMBOL	TEST CONDITION	25°C			-40 ~ 85°C		UNIT	
			V _{CC}	MIN.	TYP.	MAX.	MIN.		MAX.
Minimum Serial In Set-up Time	t _s		2.0	-	25	75	-	95	ns
			4.5	-	6	15	-	19	
			6.0	-	5	13	-	16	
Minimum Strobe Set-up Time	t _s		2.0	-	50	150	-	190	
			4.5	-	13	30	-	38	
			6.0	-	11	26	-	33	
Minimum Serial In Hold Time	t _h		2.0	-	-	0	-	0	
			4.5	-	-	0	-	0	
			6.0	-	-	0	-	0	
Minimum Strobe Hold Time	t _h		2.0	-	-	0	-	0	
			4.5	-	-	0	-	0	
			6.0	-	-	0	-	0	
3-State Output Enable Time	t _{PZL}	R _L =1kΩ	2.0	-	76	150	-	190	
	t _{PZH}		4.5	-	19	30	-	38	
			6.0	-	16	26	-	33	
3-State Output Disable Time	t _{PLZ}	R _L =1kΩ	2.0	-	84	150	-	190	
	t _{PHZ}		4.5	-	21	30	-	38	
			6.0	-	18	26	-	33	
Input Capacitance	C _{IN}		-	5	10	-	10	pF	
Power Dissipation Capacitance	C _{PD} ⁽¹⁾		-	167	-	-	-		

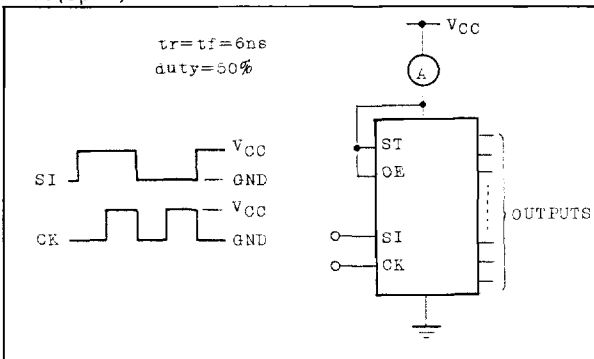
Note (1) C_{PD} is defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test Circuit). Average operating current can be obtained by the equation hereunder.

$$I_{CC(opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

SWITCHING CHARACTERISTICS TEST WAVEFORM



ICC(opr.) TEST WAVEFORM



C_{PD} CALCULATION

C_{PD} is to be calculated with the formula hereunder by using the measured value of I_{CC(opr)} in the test circuit drawn left side.

$$C_{PD} = \frac{I_{CC(opr)}}{f_{IN} \cdot V_{CC}}$$

At determining the typical value of C_{PD}, a relatively high frequency 1MHz was applied for f_{IN}, in order to eliminate the error from the quiescent supply current.